

7th



MEMUNITY -
The MEMS Test Community

Workshop



Date: Tuesday, 23rd of October 2007

Location: Conference Center the Strip
High Tech Campus Eindhoven

Room: Lorentz-Zeeman

Testing of MEMS components at different stages of fabrication and before packaging is an increasingly important challenge for achieving high yield, reliability and low production cost. Different techniques are necessary to achieve this goal. Obtain comprehensive information in this free workshop about solutions for testing MEMS at wafer-level.



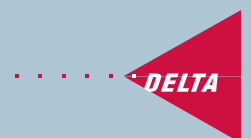
Experiences with wafer-level testing will be presented via talks including:

- Reliability Challenges of MEMS
- Probe Stations at Platforms for early MEMS Testing
- Ink-Jet Testing
- 3D Motion Characterization
- Identification of Failure Mechanisms
- Testing Resonator and Pressure Sensor MEMS
- Challenges of the right Test Stimuli

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The workshop is organized by MEMUNITY, an open community of companies and industries operating in the field of microsystems technology.

www.memunity.org



Agenda

08:45	Registration, Coffee	Reception Area "Röntgen"
09:10	Welcome by the Chairman	Lorentz-Zeeman
09:15	Newest Developments in Wafer Level MEMS Testing Carel van de Beek, SUSS MicroTec	Lorentz-Zeeman
09:40	MEMS Resonator Project Dr. Kim Le Phan, NXP Semiconductors Eindhoven	Lorentz-Zeeman
10:10	Characterization of Inkjet Actuators Frans Blom, Océ-Technologies B. V. Netherlands	Lorentz-Zeeman
10:35	Reliability Measurements of MEMS using Optical Techniques Dr. Jeroen De Coster, IMEC vzw. Belgium	Lorentz-Zeeman
11:00	Coffee and Refreshments, Demonstrations	Reception Area "Röntgen"
11:30	Microstructure Characterization Dipl.-Ing. Jens Klattenhoff, Polytec GmbH	Lorentz-Zeeman
12:00	Infrastructure & Expertise of MiPlaza Peter Kerkhofs, MiPlaza Reliability Center	Lorentz-Zeeman
12:25	Lunch	Reception Area "Röntgen"
13:30	Tour of MiPlaza Reliability Center Peter Kerkhofs, Marc Kuilder, MiPlaza Reliability Center	MiPlaza Reliability Center
14:00	Tour at Inkjet Application Center Frans Blom, Océ-Technologies B. V. Netherlands	Inkjet Application Center
14:30	Explosive Microbubble Actuator Ir. Dennis van den Broek, MESA+ Institute for Nanotechnology, University of Twente	Lorentz-Zeeman
15:00	Coffee with American Sweets, Demonstration	Reception Area "Röntgen"
15:30	SOI Devices and Ring Oscillators on Thin Dielectric Membranes For Pressure Sensing Applications Benoit Olbrechts, Université Catholique de Louvain Belgium	Lorentz-Zeeman
16:00	Development and Characterization of AlN Resonators and a resonant fluid density meter Ir. Marcel Dijkstra, MESA+ Institute for Nanotechnology, University of Twente	Lorentz-Zeeman
16:30	Forum Discussion and Demonstrations	Lorentz-Zeeman
17:00	Informal Meeting, Drinks will be served	Reception Area "Röntgen"
18:00	End	

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